Search Notes

Application/Control No.	Applicant(s)/Patent und r Reexamination
10/736,256	BATNI ET AL.
Examin r	Art Unit
CongVan Tran	2617

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	SEAR	CHED				
Class	Subclass	Date	Examiner			
455	406 408 414.1 445	5/25/2006	ст			
379	114.05	5/26/2006	СТ			
 	114.06					
	114.2					
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INI	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
455	445 406	5/26/2006	СТ		
379	114.2	5/26/2006	СТ		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
		DATE	EXMR	
Search Updated		5/26/2006	ст	
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